

ABSTRACT

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A measuring setup (100, 10, 140) for measuring an optical device under test – DUT- (120) comprises an optical signal source (100) for applying an optical signal to the DUT (120), and an optical receiver unit (140) for measuring a response of the DUT (120) on the applied signal. A measurement unit (10) is coupled between the optical signal source (100) and the optical receiver unit (140). The measurement unit (10) comprises an optical circuit (20) to provide optical signals from and/or to the DUT (120) for measuring the DUT (120), whereby the optical circuit (20) comprises optical components (130) showing high susceptibility to mechanical noise. A shielding unit (30, 40) receives the optical circuit (20) and provides at least partial shielding of the optical circuit (20) and/or the DUT (120) against mechanical noise.

[Fig. 1 for publication]